Notice of Allowability	Application No.	Applicant(s)	
	10/662,830	HOLLMAN, KENNETH F.	
	Examiner	Art Unit	
	Ernest F. Karlsen	2829	
The MAILING DATE of this communication apperall claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in the or other appropriate communic GHTS. This application is sub-	is application. If not inclu cation will be mailed in du	ded e course. <b>THIS</b>
1. This communication is responsive to the filing of September	e <u>r 15, 2003</u> .		
2. The allowed claim(s) is/are <u>1-22</u> .			
3. 🛮 The drawings filed on <u>15 September 2003</u> are accepted by	the Examiner.		
<ul> <li>4. Acknowledgment is made of a claim for foreign priority unall a) All b) Some* c) None of the: <ol> <li>Certified copies of the priority documents have</li> <li>Certified copies of the priority documents have</li> <li>Copies of the certified copies of the priority documents have</li> <li>International Bureau (PCT Rule 17.2(a)).</li> </ol> </li> <li>* Certified copies not received: <ol> <li>Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.</li> </ol> </li> </ul>	been received. been received in Application for this communication to file a	No  In this national stage applic	
5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give		_	NOTICE OF
<ul> <li>6. CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date</li> <li>(b) including changes required by the attached Examiner's Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the deposit of the deposit of</li></ul>	son's Patent Drawing Review ( . s Amendment / Comment or in .84(c)) should be written on the che header according to 37 CFR of BIOLOGICAL MATER	the Office action of drawings in the front (not to 1.121(d).	
<ul> <li>Attachment(s)</li> <li>1. ☑ Notice of References Cited (PTO-892)</li> <li>2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 0903</li> <li>4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material</li> </ul>	6. Interview Sum Paper No./Ma 08), 7. I Examiner's Ar	mal Patent Application (Pamary (PTO-413), ail Datenendment/Comment atement of Reasons for A	, in the second
		PRIMARY EXAMINER	

U.S. Patent and Trademark Office PTOL-37 (Rev. 1-04) Art Unit: 2829

## **Reasons for Allowance**

No reference was found anticipating or a combination of references found making obvious a probe station system comprising a platform for positioning a microscope or a microscope, a support for a specimen, apparatus for acquiring an image identifying conductive path indicia of the surface of the specimen from the microscope, probe control apparatus for controlling a plurality of positionable probes, a vacuum chamber, feedthrough apparatus for conducting a signal to remotely control the probes, wherein the apparatus for acquiring an image controls the probe control apparatus using the acquired image to identify the electrically conductive terminals from the conductive path indicia of the surface of the specimen observed with the microscope. No reference was found anticipating or a combination of references found making obvious a method of analyzing an integrated circuit specimen comprising positioning a microscope for observing a specimen on a support, acquiring an image identifying conductive path indicia of the surface of the specimen from the microscope, remotely controlling a plurality of probes in a vacuum chamber in which a vacuum is generated, the chamber holding the microscope and the specimen and coupling signals via a feedthrough on the chamber for applying electrical test signals to the terminals of the specimen by remotely controlling the probes using the conductive path indicia of the surface of the specimen observed with the microscope.

## **Examiner's Amendment**

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided

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by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

In the specification, page 1, line 4, before "which", --now U.S. Patent No. 6,621,282, -- has been inserted.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Kasai et al and Todokoro are cited to show prior art where an electron beam microscope where probe tips contacting a semiconductor device under test are in the field of view of the electron beam microscope.

Claims 1-22 are allowed.

Any inquiry concerning this communication should be directed to Ernest F. Karlsen at telephone number 571-272-1961.

Ernest F. Karlsen

June 25, 2004

ERNEST KARLSEN PRIMARY EXAMINER